



Editorial

H. J. Caulfield, Editor

A "Perfectionist" Reviewer

Over a period of years an editor deals with numerous reviewers—most of them careful and thorough in their task. To these reviewers we owe much gratitude and praise, but it is not of them I now write. I want to comment instead on the reviewer who might be described as a perfectionist.

I recently received a review that strikes me as perfectionist in the extreme. The reviewer made several valuable suggestions that I urged the authors to accept. But he also made numerous suggestions that, in my opinion, were more in the nature of nit-picking. These comments were well intended and quite possibly correct. Yet, it seems to me that there is an assumption implicit in the reviewer's comments that there is a right way to write a scientific paper. That is not my belief, and thus I strive to preserve each author's right to his own style. The reviewer's idea of perfection may not be the same as the author's.

If it is true, as I have so often observed, that science is primarily a human activity, then we must expect a great diversity of style in scientific writing. Creativity is not compatible with uniformity. I treasure the former and must, therefore, willingly forgo the latter.

I have only two guidelines for authors: First, write a paper you would enjoy reading. Don't make the reader suffer. Second, lure the reader into your paper with a carefully crafted title, abstract, and introduction. Beyond that, your style is, and should be, your own.

OPTICAL ENGINEERING EDITORIAL SCHEDULE

May/June 1985

Surface Metrology

Theodore Vorburger
A117 Metrology
National Bureau of Standards
Gaithersburg, MD 20899
301/921-2159

Image and Hologram Data Reduction

James D. Trolinger
Spectron Development Laboratories, Inc.
3303 Harbor Blvd., Suite G-3
Costa Mesa, CA 92626
714/549-8477

July/August 1985

Holographic Interferometry

Ryszard Pryputniewicz
Worcester Polytechnic Institute
Dept. of Mechanical Engineering
Worcester, MA 01609
617/793-5536

Nonlinear Optical Materials, Devices, and Applications

Mario Dagenais
GTE Laboratories, Inc.
40 Sylvan Road
Waltham, MA 02254
617/890-8460

September/October 1985

Holography

Lloyd Huff
University of Dayton Research Institute
300 College Park
Dayton, OH 45469
513/229-2113

November/December 1985

Optical Inspection

Donald Sweeney	Timothy C. Strand
Sandia National Labs.	IBM Research Lab.
MS ORG8354	K46/282
Livermore, CA 94550	5600 Cottle Rd.
415/422-3138	San Jose, CA 95193
	408/284-8919

Spectral Pattern Recognition

O. I. Sindoni
USAMCCOM, CRDC,
Research Directorate, Physics Div.
SMCCR-RSP-B, Bldg. E5951
Aberdeen Proving Ground, MD 21010
301/671-4256